Detector K08-W0276

1 Detector Details and Basic Parameters

Readout: MiniPIX (sn: 107) **Full Name:** MiniPIX K08-W0276

Chip: Timepix **Sensor:** Si $(300 \ \mu m)$

 Temperature:
 22.0

 Pixet Version:
 1.4.10.706

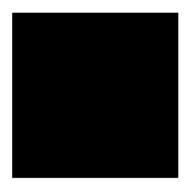
 TpxSetup Version:
 1.9 (31.7.2018)

 Date:
 04.10.2018 11:36:09

Responsible: Matous

Parameter	Value	Reason	
Timepix Clock	10.0	Noise reduction	
Ikrum	1	Better energy resolution	
FBK	159	Wider energy range in ToT mode	
THL Coarse	8	Wider energy range of threshold	
Preamp	225	Lower power consumption and heat	

2 Digital Test and Bias Test

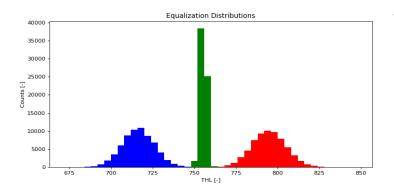


Bad Pixels: 0

3 Bias Leakage Test

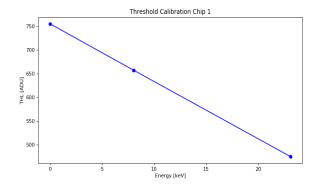
Bias [V]	Leaking Pixels [cnt]	Leaking Current [μA]	Voltage Sense [V]
0	0.0000	0.0000	0.0000
20	0.0000	0.0000	0.0000
40	0.0000	0.0000	0.0000
60	0.0000	0.0000	0.0000
80	0.0000	0.0000	0.0000
100	0.0000	0.0000	0.0000
120	0.0000	0.0000	0.0000
140	0.0000	0.0000	0.0000
160	0.0000	0.0000	0.0000
180	0.0000	0.0000	0.0000
200	0.0000	0.0000	0.0000

4 Threshold Equalization



Parameter	Value
Mean THL	755.465
Std. Dev	2.183
Masked Pixels	3
Final THL	722

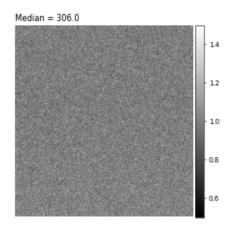
5 Threshold Energy Calibration

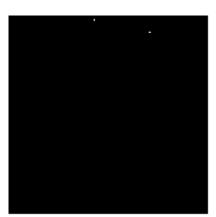


A 12.104 B 45.366 W 0.179 T 6.597 K 1.000 Min. Threshold 2.696 keV THL 5 keV 694.112	Parameter	Value
W 0.179 T 6.597 K 1.000 Min. Threshold 2.696 keV	A	12.104
T 6.597 K 1.000 Min. Threshold 2.696 keV	В	45.366
K 1.000 Min. Threshold 2.696 keV	\mathbf{W}	0.179
Min. Threshold 2.696 keV	T	6.597
21070 110	K	1.000
THL 5 keV 694.112	Min. Threshold	2.696 keV
	THL 5 keV	694.112

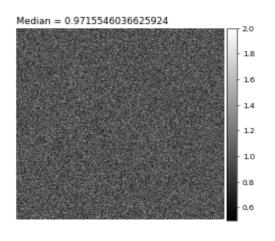
Bad Pixels: 5

6 Bad Pixels Test with X-Ray

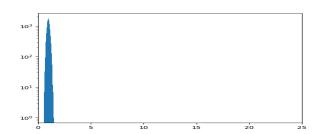




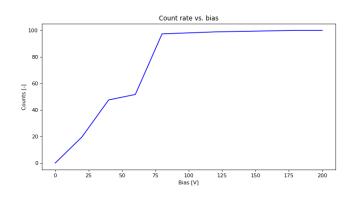
7 Stability Test with Cd XRF 23.106 keV, duration: 10.0 min



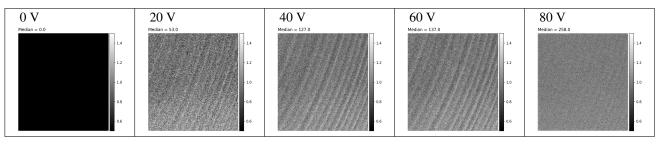
Median:0.972Pixel Median Range:0.5-2.0Deviating Pixels 2 σ :0.006%Deviating Pixels 5 σ :0.005%Global Stability:0.120%

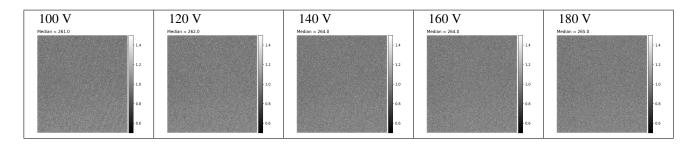


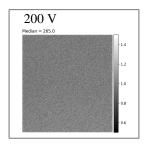
8 Bias Test with Fe XRF (6.4keV)



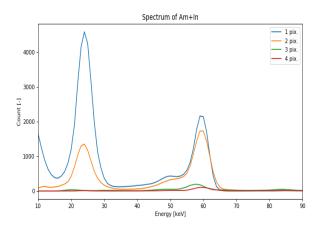
Parameter	Value
Bias From	160
Bias To	200
Bias Step	20







9 Energy Calibration in ToT Mode

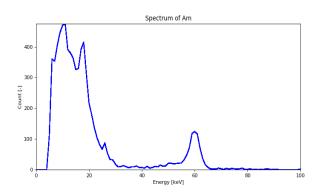


Source	Energy	1	2	3	4
Fe	5.862	5.408	10.579	3.000	3.000
In	24.189	24.053	23.706	19.768	23.696
Am	59.472	59.579	59.630	57.908	59.764

Coefficient	Mean value
A	1.690
В	27.250
C	28.905
T	4.190

10 Calibration Verification

Verification from the front side of the detector



Source	Energy	Sigma
Am	59.585	2.693

11 Summary and Classification

Calibrated for threshold of 5 keV (THL=694)

Criterion	Value	Unit	Class
ROC (Wafer probing result)	-	-	A
Masked pixels	3	cnt	A
Bad pixels after test with sources	5	cnt	Α
Largest bad cluster pixel count	3	cnt	Α
Min. threshold Medipix mode	2.696	keV	AA
Energy resolution ToT at 60 keV	2.012	keV	A

Final Statement	Class	Verbal
Imaging applications (Counting mode)	A	Very good
Tracking applications (Energy mode)	A	Very good